


<b>Search Notes</b>  	<b>Application/Control No.</b>  10662931	<b>Applicant(s)/Patent Under Reexamination</b>  CURTISS ET AL.
	<b>Examiner</b>  Pardo, Thuy N	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner
707	10	8/30/2007	TP
455	186.1	8/30/2007	TP
715	210, 802	2/16/2008	TP
707	10	9/28/2008	TP
715	802	9/28/2008	TP
707	2, 3, 5,7, 101, 102, 104.1	4/9/2009	TP

SEARCH NOTES			
Search Notes		Date	Examiner
WEST		8/30/2007	TP
WEST, NPL (IEEE)		2/16/2008	TP
WEST, NPL (ACM)		9/28/2008	TP
WEST, Google Scholar, Multiple Databases		4/9/2009	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
707	2, 3, 5,7, 10, 101, 102, 103, 104.1	4/9/2009	TP
455	186.1	4/9/2009	TP
715	210, 802	4/9/2009	TP

		/Thuy N Pardo/ Primary Examiner.Art Unit 2627
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